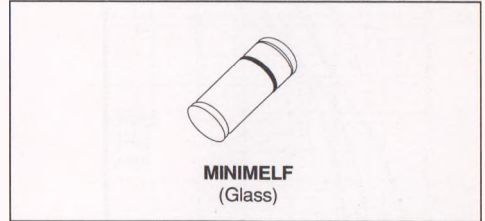


**SMALL SIGNAL SCHOTTKY DIODE**
**DESCRIPTION**

General purpose metal to silicon diode featuring very low turn-on voltage and fast switching.

This device has integrated protection against excessive voltage such as electrostatic discharges.


**ABSOLUTE RATINGS** (limiting values)

Symbol	Parameter	Value	Unit
$V_{RRM}$	Repetitive Peak Reverse Voltage	100	V
$I_F$	Forward Continuous Current	$T_I = 25^\circ\text{C}$	100 mA
$I_{FRM}$	Repetitive Peak Forward Current	$t_p \leq 1\text{s}$ $\delta \leq 0.5$	350 mA
$I_{FSM}$	Surge non Repetitive Forward Current	$t_p = 10\text{ms}$	750 mA
$P_{Tot}$	Power Dissipation	$T_I = 95^\circ\text{C}$	100 mW
$T_{stg}$ $T_j$	Storage and Junction Temperature Range		- 65 to 150 °C - 65 to 125 °C
$T_L$	Maximum Temperature for Soldering during 15s	260	°C

**THERMAL RESISTANCE**

Symbol	Parameter	Value	Unit
$R_{th(j-l)}$	Junction-leads	300	°C/W

**ELECTRICAL CHARACTERISTICS**
**STATIC CHARACTERISTICS**

Symbol	Test Conditions		Min.	Typ.	Max.	Unit
$V_{(BR)}$	$T_j = 25^\circ\text{C}$	$I_R = 100\mu\text{A}$	100			V
$V_F^*$	$T_j = 25^\circ\text{C}$	$I_F = 1\text{mA}$		0.4	0.45	V
	$T_j = 25^\circ\text{C}$	$I_F = 200\text{mA}$			1	
$I_R^*$	$T_j = 25^\circ\text{C}$	$V_R = 50\text{V}$			0.1	$\mu\text{A}$
	$T_j = 100^\circ\text{C}$				20	

**DYNAMIC CHARACTERISTICS**

Symbol	Test Conditions			Min.	Typ.	Max.	Unit
C	$T_j = 25^\circ\text{C}$	$V_R = 1\text{V}$	$f = 1\text{MHz}$		2		pF

\* Pulse test :  $t_p \leq 300\mu\text{s}$   $\delta < 2\%$

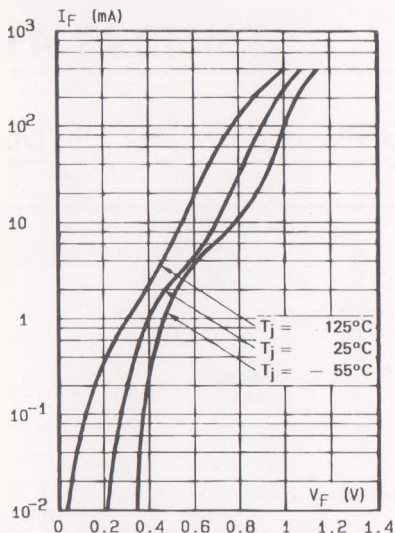


Fig.1 - Forward current versus forward voltage at different temperatures (typical values).

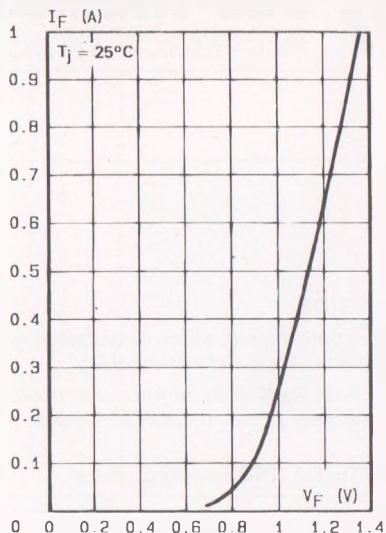


Fig.2 Forward current versus forward voltage (typical values).

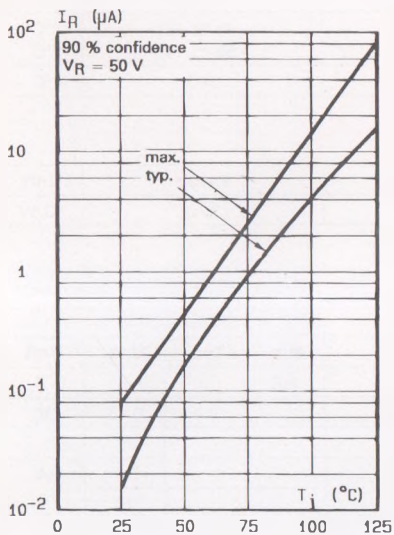


Fig.3 - Reverse current versus junction temperature.

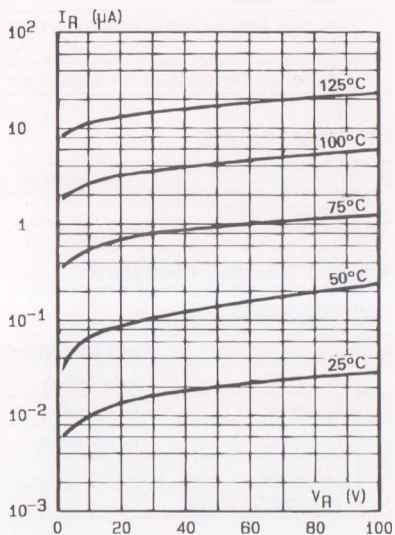


Fig.4 - Reverse current versus continuous reverse voltage (typical values).

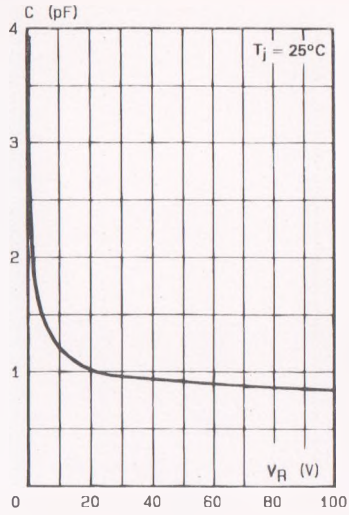


Fig.5 - Capacitance  $C$  versus reverse applied voltage  $V_R$  (typical values) .